Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/611,435	TAKAHASHI ET AL.	TAKAHASHI ET AL.	
Examiner	Art Unit		
James M. Hannett	2622		

James M. Hannett

	SEAD	CHĖD			
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Class	Subclass	Date	Examiner		
348	231.1 231.2 231.3 231.4 231.5	6/20/2007	ЈМН		
348	231.6	6/20/2007	JMH		

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QEM meeting Lin Ye Tuan Ho	1/17/2007	JMH
Chelcie Daye Paul Kim AU 2161 class 707	6/25/2007	JMH
James Fletcher AU 2621 Class 386	6/25/2007	JMH